

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 05-164785

(43)Date of publication of application : 29.06.1993

(51)Int.Cl.

G01R 1/073

G01R 1/067

H01L 21/66

(21)Application number : 03-330180

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(22)Date of filing : 13.12.1991

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(54) PROBE FOR SEMICONDUCTOR INTEGRATED CIRCUIT TESTER

(57)Abstract:

PURPOSE: To obtain an inspection probe which can prevent deformation of a pad of a semiconductor integrated circuit in a semiconductor integrated circuit tester.

CONSTITUTION: One edge of a probe part 32 is fixed to a probe-retention substrate 36 and a contact part 34 is joined to and placed at the other edge. The contact part 34 is constituted by a hard conductive member with the probe part 32 and the probe part 32 is constituted by a plate-shaped conductive member with plate spring elasticity.

When a probe 30 is pressed, the probe part 32 fully absorbs the press force and prevents deformation of a pad 20.

